10/551 447 JC09 Rec'd PCT#PEO 29 SEP 2005

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(Modified)		PATENT AND TRAC	DEMARK OFFICE	278377US0PCT		New U.S. PCT Application Based on PCT/JP04/04155		
				APPLICANT				
LIST OF	REFE	RENCES CITED BY AP	PLICANT	Shin-ichiro IWANAGA, et al.				
				FILING DATE		GROUP		
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U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME CLASS SUB FILING DATE IF APPROPRIATE				
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Other References FOREIGN PATENT DOGUMENTS								
		DOCUMENT	DATE	COUNTRY		TRANSLATION		
		NUMBER		NI-	_	YES	NO	
CH	AO	2003-29604	01/31/03	JP (English abstract only)	Docum		NO	
CH	AP	2002-182381	06/26/02	JP (English abstract only)	Docu	men!	NO	
CH	AQ	2000-39709	02/08/00	JP (English abstract only) JP (English abstract only & Equivalen	Do Doc	ument,	NO	
CH	AR	2000-336121	12/05/00	US 6312867)	<u> </u>	Document	NO	
CH	AS	11-271974	10/08/99	JP (English abstract only)	No	Documen	NO	
СН	AT	3-188150	08/16/91	JP (English abstract only & Equivalen US 5217847)	100	Document	NO	
CH	AU	2003-113174	04/18/03	JP (English abstract only)	No	Documen	NO	
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
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Examiner	/Pri	mary Examiner Cynthia Hamilton/				Date Considered 01/08/2007		
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